

Notice of References Cited	Application/Control No. 10/663,714	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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*	N	JP 2004-165287	06-2004	Japan	Chen et al.	
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NON-PATENT DOCUMENTS

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